

In re: Rinn
Inter'l Appl. No.: PCT/DE00/01467
U.S. Appl. No. 10/019,855
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Version with markings to show changes made

In the Specification:

The paragraph beginning at page 3, line 35 has been rewritten as follows:

--Summary of the Invention

The above and other objects and advantages of the present invention are achieved by a device of the type which [The foregoing object is accomplished by a device for examining materials with the characterizing features of claim 1. Accordingly, a device for examining materials of the initially described kind] is designed and constructed such that an electronic evaluation device is associated to each sensor.--

The paragraph beginning at page 17, line 9, has been rewritten as follows:

--There exist various possibilities of improving and further developing the teaching of the present invention in an advantageous manner. To this end, reference may be made [on the one hand to the dependent claims, and on the other hand] to the following description of an embodiment of the device according to the invention with reference to the drawing. In conjunction with the description of the preferred embodiment of the device according to the invention with reference to the drawings, also generally preferred improvements and further developments of the teaching are described. [In the drawings:]--